# G iant m agnetotherm opower of m agnon-assisted transport in ferrom agnetic tunnel junctions

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W e present a theoretical description of the therm opower due to m agnon-assisted tunneling in a m esoscopic tunnel junction between two ferrom agnetic m etals. The therm opower is generated in the course of them alequilibration between two baths of m agnons, mediated by electrons. For a junction between two ferrom agnets with antiparallel polarizations, the ability of magnon-assisted tunneling to create therm opower  $S_{A,P}$  depends on the di erence between the size ";# of the majority and m inority band Ferm is urfaces and it is proportional to a tem perature dependent factor ( $k_B$  T =!  $_D$  )<sup>3=2</sup> where !  $_{\rm D}$  is the m agnon D ebye energy. The latter factor release the fractional change in the net m agnetization of the reservoirs due to therm alm agnons at tem perature T (B both's T<sup>3=2</sup> law). In contrast, the contribution of m agnon-assisted tunneling to the therm opower SP of a junction with parallel polarizations is negligible. A sthe relative polarizations of ferrom agnetic layers can be m an ipulated by an external magnetic eld, a large di erence  $S = S_{AP} - S_{P}$  $(k_{\rm B} = e) f( _{"}; _{\#}) (k_{\rm B} T = !_{\rm D})^{3=2}$ SAP results in a magnetotherm opower e ect. This magnetotherm opower e ect becomes giant in the extrem e case of a junction between two half-m etallic ferrom agnets, S k <sub>в</sub> =е.

#### I. IN TRODUCTION

Spin polarized transport has recently been the subject of intense theoretical and experim ental interest.<sup>1</sup> The m ism atch of spin currents at the interface between two ferrom agnetic (F) electrodes with antiparallel spin polarizations produces a larger contact resistance than a junction with parallel polarizations, leading to tunneling m agnetoresistance in F-F junctions<sup>2,3</sup> and giant m agnetoresistance (GMR) in multilayer structures.<sup>4,5</sup> System s displaying GMR have shown other m agnetotransport e ects including substantial m agnetotherm opow er<sup>6</sup><sup>{15</sup></sup> with a strong tem perature dependence. Therm oelectric e ects have also been discussed in the context of spin injection across a ferrom agnetic-param agnetic junction.<sup>16</sup>

The M ott form  $ula^{17} S = ({}^{2}k_{B}^{2}T=3e)$  (@ ln ()=0)<sub>F</sub> relates the therm opower S of a system to the derivative with respect to energy of the electrical conductivity,

( ), near the Ferm i energy,  $_{\rm F}$ , so that, in m etals, S typically contains a sm all param eter such as  $k_{\rm B}$  T =  $_{\rm F}$ . In m agnetic multilayers with highly transparent interfaces, the M ott form ula has been used as a basis for theories of transport that explain the origin of the m agnetotherm opower e ect as due to either the di erence in the energy dependence of the density of states form a jority and m inority spin bands in ferrom agnetic layers,  $^{13;18}$  or a different e ciency of electron-m agnon scattering for carriers in opposite spin states.<sup>8</sup> In particular, the electron-m agnon interaction in a ferrom agnetic layer was incorporated to explain the observation  $^8$  of a strong tem perature dependence of S (T ) and gave, theoretically, a much larger them opower in the parallel con guration of multilayers with highly transparent interfaces than in the antipar-

allel one,  $S_P$   $S_{A\,P}$ . For tunnel junctions, m agnonassisted processes have been studied both theoretically  $^{19}$  and experim entally  $^{20}$  with a view to relate nonlinear I (V) characteristics to the density of states of m agnons (!) as  $d^2 \, I = dV^2 /$  (eV).

In this paper we investigate a model of the electronm agnon interaction assisted therm opower in a mesoscopic size ferrom agnet/insulator/ferrom agnet tunnel junction, which yields a di erent prediction. The bottleneck ofboth charge and heat transport lies in a sm all-area tunnel contact between ferrom agnetic metals held at different tem peratures. The therm opower is generated in the course of therm al equilibration between two baths of m agnons as mediated by electrons, and, in the relatively high resistance antiparallel (AP) con guration of a ferrom agnetic tunnel junction, it depends on the di erence between the size of therm a jority and m inority band Ferm i surfaces. For a momentum -conserving tunneling model we nd that

$$S_{AP} = \frac{k_B}{e} \frac{(+)}{2} m(T);$$
 (1)

m (T) = 
$$\frac{3:47}{\frac{1}{2}} \frac{k_{\rm B}T}{\frac{1}{2}}$$
; (2)

where  $_{+}$  ( ) is the area of the m axim alcross-section of the Ferm i surface of majority (m inority) electrons in the plane parallel to the interface ( $_{+}$  > ). The function m (T) is the fractional change in the magnetization of the reservoirs due to therm alm agnons at temperature T (B loch's T<sup>3=2</sup> law), is the spin of localized moments,

and  $!_{\rm D}\,$  is the m agnon D ebye energy. On the other hand, we nd that the contribution of m agnon-assisted tunneling to the therm opower of a parallel con guration is negligible.

As an extrem e example, the magnetotherm opower effect is most pronounced in the case of halfmetallic ferrom agnets, where the exchange spin splitting between the majority and minority conduction bands is greater than the Ferm i energy  $_{\rm F}$  measured from the bottom of the majority band, and the Ferm i density of states in the minority band is zero. In the antiparallel con guration of such a junction, where the emission/absorption of a magnon would lift the spin-blockade of electronic transfer between ferrom agneticmetals, we predict a large therm opower e ect, whereas in the lower-resistance parallel con guration therm opower is relatively weak:<sup>21</sup>

$$S_{AP} = 0.64 \frac{k_B}{e}; \frac{S_P}{S_{AP}} \frac{k_B T}{F};$$
 (3)

This is because the contribution of magnon-assisted transport to the therm opower in the parallel con guration  $S_P$  is zero and the therm opower only arises from the energy dependence of the electronic density of states near the Ferm i energy.

The magnon-assisted processes that we consider are similar to those discussed in Refs. 19 in relation to the magnon contribution to the nonlinear conductance. In a ferrom agnetic tunnel junction in the antiparallel con guration, the elastic contribution to the conductance is suppressed by them ism atch of spin currents at the interface. How ever it is possible to lift spin currents blockade while conserving the overall spin of the system by emitting or absorbing magnons. For example, the change of spin that occurs when a minority carrier ips and occupies a majority state is compensated by an opposite change of spin due to magnon emission. As a result, the spin current carried by electrons crossing an interface between oppositely polarized ferrom agnets is carried further by the ow of magnons (spin waves).

M icroscopically, a typical m agnon-assisted process that contributes to the therm opower in the antiparallel con guration, Eqs. (1) and (3), is shown schematically in Figure 1. Here the majority electrons on the left hand side of the junction are 'spin-up' and the majority electrons on the right are 'spin-down'. The transition begins with a spin-up majority electron on the left, that then tunnels through the barrier (without spin ip) into an interm ediate, virtual state with spin-up m inority polarization on the right (Figure 1(a)). In the nal step, Figure 1 (b), the electron em its a magnon and incorporates itself into a previously unoccupied state in the spin-down majority band on the right. In our approach, we take into account such inelastic tunneling processes that involve magnon emission and absorption on both sides of the interface, as well as elastic electron transfer processes, in order to obtain a balance equation for the current I (V; T) as a function of bias voltage, V, and of

the tem perature drop, T. In the linear response regime the electrical current m ay be written as

$$I = G_V V + G_T T; \qquad (4)$$

where  $G_V$  is the electrical conductance and  $G_T$  is a therm oelectric coe cient describing the response to a tem – perature di erence. Under conditions of zero net current, the therm opower coe cient is

$$S = \frac{V}{T} = \frac{G_{T}}{G_{V}} :$$
 (5)

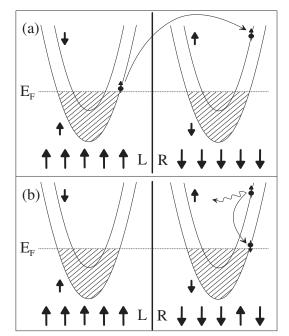


FIG.1. Schem atic of m agnon-assisted tunneling via an interm ediate m inority state. This example shows a transition from an initial majority state on the left to a nalmajority state on the right across a junction in the anti-parallel con guration. (a) The process begins with a spin-up majority electron on the left, that then tunnels through the barrier (without spin ip) into an interm ediate, virtual state with spin-up m inority polarization on the right. (b) The electron emits a magnon (wavy line) and incorporates itself into a previously unoccupied state in the spin-down majority band on the right.

The paper is organised as follows. In Section II we introduce the model and technique used for describing a tunnel junction and we calculate the therm opower in the antiparallel (AP) con guration. We present a detailed description of two di erent models of the interface: a uniform ly transparent interface where the component of momentum parallel to the interface is conserved, and a random ly transparent interface. In Section III we dem onstrate that the contribution of magnon-assisted tunneling to the therm opower of a parallel (P) con guration is negligible. In Section IV we discuss the magnetotherm opower, give an order of magnitude estim ate of the size

of the e ect, and present results for the magnetothermopower of a junction between two half-metallic ferromagnets.

# II. THERM OPOW ER OF AN ANT IPARALLEL JUNCTION

## A .D escription of the m odel

Our initial aim is to write a balance equation for the current in terms of occupation numbers of electrons  $n_{L(R)}(k) = \exp((k - \frac{L(R)}{F}) = (k_{B}T_{L(R)}) + 1]^{-1}$  and of magnons N<sub>L(R)</sub> (q) =  $[exp(!_q = (k_B T_{L(R)})) - 1]^1$  on the left (right) hand side of the junction, where  $T_{L(R)}$  is the tem perature on the left (right) hand side,  $\frac{L}{F} = \frac{R}{F}$ eV, and  $!_q$  is the energy of a m agnon of wavevector q. In the following we set  $T_L = T$  and  $T_R = T$  T and we shall speak throughout in terms of the transfer of electrons with charge e. The index = f+; g takes account of the splitting of conduction band electrons into majority  $_{k+}$  and m inority  $_{k}$  subbands,  $_{k} = _{k}$ =2, where  $_k$  is the bare electron energy and is the spin splitting energy.

In an AP junction, we assume that the majority electrons on the left hand side of the junction are spin-up' and the majority electrons on the right are spin-down'. The total Ham iltonian of the system is

$$H = H_{F}^{L} + H_{F}^{R} + H_{T};$$
(6)

$$H_{T} = \int_{kk^{0}}^{t} t_{k,k^{0}} c_{k}^{Y} c_{k,\sigma} + t_{k,k^{0}} c_{k,\sigma}^{Y} - c_{k} ; \qquad (7)$$

where H<sub>T</sub> is the tunneling H am iltonian<sup>22 {24</sup> that is w ritten in term s of creation and annihilation Ferm ioperators c<sup>y</sup> and c. Here and we assume that spin is conserved when an electron tunnels across the interface. The tunneling m atrix elements  $t_{k\, jk^0}$  describe the transfer of an electron w ith w avevector k on the left to the state w ith k<sup>0</sup> on the right. W e w ill consider  $t_{k\, jk^0}$  to be a symmetric m atrix of the form

$$t_{k,k^{0}} = t_{k,j,k^{0},j} \frac{h^{2} v_{L}^{z} (k) v_{R}^{z} (k^{0})}{L^{2}} i^{1=2};$$
(8)

where  $v_{L\,;R}^{z}(k) = (l_{L\,;R}(k)) = (l_{R\,;R}(k))$  are components of electron velocity perpendicular to the interface and  $L_{;R}(k)$  denotes the electron energy dispersion in the electrodes. In our model for t, we neglect its explicit energy dependence. However,  $t_{k\,;j;k\,^{0};j}$  can describe both clean and di usive interfaces by taking into account the conservation of  $k_{jj}$ , the component of momentum parallel to the interface.

the interface. The term H  $_{\rm F}^{\rm L~(R)}$  is the H am iltonian of the ferrom agnetic electrode on the left (right) side of the junction in the absence of tunneling. We use the so called s-f (s-d) m odel,<sup>25;26</sup> which assumes that m agnetism and

electrical conduction are caused by di erent groups of electrons that are coupled via an intra-atom ic exchange interaction, although we note that the same results, in the lowest order of electron-m agnon interactions, m ay be obtained from a model of itinerant ferrom agnets.<sup>27</sup> The magnetism originates from inner atom ic shells (e.g., d or f) which have unoccupied electronic orbitals and, therefore, possess m agnetic m om ents w hereas the conduction is related to electrons with delocalized wave functions. U sing the Holstein-P rim ako transform ation<sup>28</sup> the operators of the localized m om ents in the interaction H am iltonian can be expressed via magnon creation and annihilation operators by; b. At low tem peratures, where the average number of magnons is small  $< b^{y}b >$ 2 ( is the spin of the localized m om ents), the H am iltonian of the ferrom agnet H  $_{\rm F}^{\rm L~(R)}$  can be written as follows

$$H_{F}^{L(R)} = H_{e}^{L(R)} + H_{m}^{L(R)} + H_{em}^{L(R)};$$
(9)

$$H_{e}^{L(R)} = {}^{X}_{k} C_{k}^{y} C_{k}; \quad k = k = 2; \quad (10)$$

$$H_{m}^{L(R)} = \begin{array}{c} X \\ {}_{q} b_{q}^{y} b_{q}; \\ {}_{q=0} = !_{0}; \end{array}$$
(11)

$$H_{em}^{L(R)} = \frac{P_{m}}{2 N} \sum_{kq}^{X} c_{k}^{Y} c_{k} b_{q}^{Y} + c_{k}^{Y} c_{k} c_{q} + b_{q}^{Y}; (12)$$

The rst term  $H_e^{L(R)}$ , Eq. (10), deals with conduction band electrons which are split into majority  $_{k+}$  and minority  $_k$  subbands due to the s-f (s-d) exchange. The Ham iltonian  $H_m^{L(R)}$ , Eq. (11), describes free magnons with spectrum  $!_q$  which in the general case has a gap  $!_{q=0} = !_0$ . The third term  $H_{em}^{L(R)}$ , Eq. (12), is the electron-magnon coupling resulting from the intra-atom ic exchange interaction between the spins of the conduction electrons and the localized moments.

The calculation is performed using standard second order perturbation theory. We write the total H am iltonian, Eq. (6), as  $H = H_0 + V$ , where the perturbation  $V = H_T + H_{em}^{L} + H_{em}^{R}$  is the sum of the tunneling H am iltonian and the electron-m agnon interactions in the electrodes. First order terms provide an elastic contribution to the current that do not involve any change of the spin orientation of the itinerant electrons, whilst second order terms account for inelastic, m agnon-assisted processes.

#### B.Elastic contribution to the current

The rst order contribution to the current, in the antiparallel con guration, arises from elastic tunneling without any spin ip between a majority conduction electron state on one side of the junction and a minority state

on the other. Consider for example an initial state consisting of an additional majority spin up electron on the left with wavevector  $k_L$  and energy  $k_L + \cdot$ . This electron can tunnel, with matrix element  $t_{LR}$ , into a minority spin up state on the right with wavevector  $k_R$  and energy  $k_R$ . In addition there is a second process which is a transition between the same two states, but in the reverse order, giving a contribution to the current with an opposite sign. Together, the two processes give a balance equation for the rst order contribution to the current between the majority band on the left and the minority on the right. In addition, there are two rst order processes that result in transitions between the minority band on the left and the majority band on the left and the minority band on the left and the minority band on the left and the minority band on the left and the majority band on the left and the minority band on the left and the minority band on the left and the majority band on the left and the minority band on the left and the majority band balance bala

$$I_{AP}^{(1)} = 4 \frac{2}{h} \frac{e^{\sum +1}}{n} \frac{X X}{d} \frac{f_{k_{L};k_{R}}}{f_{k_{L};k_{R}}} \frac{f}{j} (k_{L})$$

$$(eV_{k_{R}}) n_{L}(k_{L}) [1 n_{R}(k_{R})]$$

$$[1 n_{L}(k_{L})]n_{R}(k_{R}) \frac{e^{-2\pi i k_{L}}}{i} (13)$$

and  $\overline{\phantom{a}}$  . N eglecting terms that contain the small parameter  $k_B$  T =  $_F$  , the current m ay be written as

$$I_{AP}^{(1)} = \frac{e^2}{h} V (T_+ + T_+):$$
 (14)

For convenience we have grouped all the information about the nature of the interface into a parameter T  $_{\circ}$ ,

$$T \circ 4^{2} \int_{k_{L}k_{R}} f(k_{L}, k_{R}) \int_{k_{L}} f(k_{L}) (k_{R}, 0); (15)$$

that is equivalent to the sum over all scattering channels, between spin states on the left and  $^{0}$  on the right, of the transm ission eigenvalues usually introduced in the Landauer form ula,  $^{30}{}^{32}$  although we restrict ourselves to the tunneling regime in this paper. Later we will employ models of two types of interface explicitly: a uniform ly transparent interface where the component of momentum parallel to the interface is conserved, and a random ly transparent interface.

## $\ensuremath{\mathtt{C}}$ . M agnon-assisted contribution to the current

Below we describe processes which contribute to m agnon-assisted tunneling. For convenience, we divide them into two groups that we label as 'electron' and hole' processes. In 'electron' processes, an increase in the number of m agnons in one electrode is achieved by accepting electrons from the other electrode whereas, in hole' processes, an increase in the number of m agnons in one electrode is achieved by injecting electrons into the other electrode.

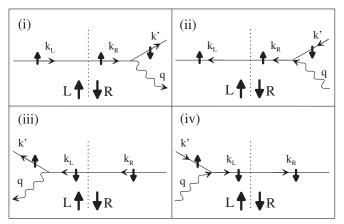


FIG.2. Schem atic of four Electron' type processes, across a junction in the antiparallel con guration, that involve transitions from majority initial to majority nal states via a virtual intermediate state in the minority band: (i) and (iii) involve magnon emission on the right and left hand sides, respectively, whereas (ii) and (iv) involve magnon absorption on the right and left.

The 'electron' processes are shown schematically in Figure 2. The straight lines show the direction of electron transfer, whereas the wavy lines denote the em ission or absorption of m agnons. The processes are drawn using the rule, appropriate for ferrom agnetic electronm agnon exchange, that an electron in a m inority state scatters into a majority state by emitting a magnon. The 'electron' processes in Figure 2 involve transitions from majority initial states to majority nal states via an interm ediate, virtual state in the m inority band. For example, process (i), which is the same as the process shown in more detail in Figure 1, begins with a spinup majority electron on the left with wavevector  $k_{I_{i}}$  and energy kL+ . Then, this electron tunnels across the barrier (without spin ip) to occupy a virtual, interm ediate state with wavevector  $k_R$  in the spin up m inority band on the right as depicted in the right part of Figure 1 (a) with energy  $_{k_{\scriptscriptstyle \mathrm{R}}}$  . The energy dierence between the states is  $k_{R}$  $k_{\rm L}$  + so that the matrix element for the transition contains an energy in the denom inator related to the inverse lifetim e of the electron in the virtual state. For k<sub>B</sub> T; eV , when both initial and nalelectron states should be taken close to the Ferm i level, only long wavelength m agnons can be em itted, so that the energy de cit in the virtual states can be approximated as . As noticed in Refs. 25,33,34, this k. + k<sub>R</sub> cancels out the large exchange param eter since the sam e electron-core spin exchange constant appears both in the splitting between m inority and majority bands and in the electron-m agnon coupling.

The second part of the transition is sketched in Figure 1 (b) where the electron in the virtual minority spin up state incorporates itself into a state in the majority spin down band on the right by emitting a magnon, which is shown as a ip of one of the localized moments. The wavevector of the electron in the nal state is  $k^0$  and the total energy of the nal (m any body) state is  $_{\rm K^{0+}}$  !<sub>q</sub>. Similiar considerations enable us to write down the contribution to the current from all the electron' processes in F igure 2. We group the processes into pairs which involve transitions between the same series of states, but in the opposite time order so that they give a current with di erent signs, hence their sum gives a balance equation. The contributions to the current of the processes (i) and (ii), labelled as  $I_{\rm A,P}^{(i;ii)}$ , are given by

$$I_{AP}^{(i;ij)} = 4 \frac{2}{n} \frac{e}{h} \frac{Z_{+1}}{1} d \frac{X_{k_{L};k^{0}q}}{k_{k_{L}k^{0}q}} \frac{J_{k_{L};k^{0}}J^{2}}{2N}$$

$$n (k_{L}+) (eV_{k^{0}+} !_{q})$$

$$n_{L} (k_{L}+) [I_{R} (k^{0}+)] [I_{L}+N_{R} (q)]$$

$$O$$

$$[I_{R} (k_{L}+)]n_{R} (k^{0}+)N_{R} (q); (16)$$

where  $q = k_R$   $k^0$ . The processes (iii) and (iv) are similar to processes (i) and (ii), respectively, except that electrons interact with m agnons in the left electrode:

$$I_{AP}^{(\text{iii};\text{iv})} = 4 \frac{2}{h} \frac{e}{h} \frac{\sum_{k=1}^{L} 1}{1} \frac{d}{k^{0}k_{R}q} \frac{\frac{1}{2}k^{0}k_{R}}{2} \frac{1}{2} \frac{1}{N}$$

$$(eV_{k_{R}}+) (k^{0+} |q)$$

$$n_{R}(k_{R}+) [1 n_{L}(k^{0+})] [1 + N_{L}(q)] + \frac{1}{N}$$

$$+ [1 n_{R}(k_{R}+)] n_{L}(k^{0+}) N_{L}(q); (17)$$

where  $q = k_L$   $k^0$ . Energies on the right are shifted by eV to take account of the voltage di erence across the junction.

An example of a hole' process is shown in detail in Figure 3 (a) and (b), and Figure 3 (c) shows the same process, (v), plus other hole' processes (vi), (vii), (viii). The hole' processes involve transitions from m inority initial to m inority nalstates via a virtual interm ediate state in them a prity band. In contrast to the 'electron' processes, an increase in the num ber of m agnons in one electrode is achieved by injecting electrons into the other electrode. As an example we describe in detail the calculation of the matrix element for process (v) shown in Figure 3 (a) and (b). The initial state has an additional spin down m inority electron near the Ferm i level on the left (left part of Figure 3(a)) with wavevector  $k_{L}$ . The rst step in the transition is the creation of an empty state below the Ferm i level in the spin down majority band on the right with wavevector  $k_R$  by the absorption of a magnon, wavevectorq, to elevate a spin down m a jority electron up to a spin up m inority state above the Ferm i level on the right with wavevector  $k^0$  (right part of Figure 3(a)). The second part of the transition is sketched in Figure 3(b) where the spin down m inority electron on the left tunnels across the barrier (without spin ip) to occupy the em pty spin down m a jority state on the right. The contributions to the current from processes (v) and (vi),  $I_{\rm A\,P}^{\rm (v,vi)}$  , and from processes (vii) and (viii),  $\rm I_{A\,P}^{(\rm viii,\rm viii)}$  , are

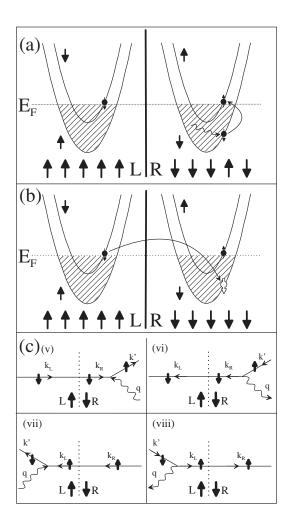


FIG.3. Schem atic of hole' type processes of magnonassisted tunneling from an initial minority state to a nal minority state via an intermediate majority state. (a) A typical process begins with the absorption of a magnon (wavy line) to elevate a spin-down majority electron below the Fermi level  $E_F$  on the right up to a spin-up minority state above  $E_F$ , creating an empty state below  $E_F$  in the spin-down majority band. (b) A spin-down minority electron on the left tunnels across the barrier (without spin ip) to occupy the empty spin down majority state on the right. (c) The same process (v) plus remaining hole' processes: (v) and (vii) involve magnon absorption on the right and left hand sides, respectively, whereas (vi) and (viii) involve magnon emission on the right and left.

$$I_{AP}^{(v;vi)} = 4 \frac{2}{n} \frac{e}{h} \frac{Z_{+1}}{1} d \frac{X_{k_{L}k^{0}q}}{k_{k_{L}k^{0}q}} \frac{J_{k_{L}k^{0}} \int_{2}^{2}}{2 N}$$

$$n (k_{L}) (eV_{k^{0}} + !_{q})$$

$$n_{L} (k_{L}) [I n_{R} (k^{0})] N_{R} (q)$$

$$[I n_{L} (k_{L})] n_{R} (k^{0}) [I + N_{R} (q)] \stackrel{\circ}{:} (18)$$

$$I_{AP}^{(vii;viii)} = 4^{2} \frac{e}{h} \frac{Z_{+1}}{1} d \frac{X_{k^{0}k_{R}q}}{\frac{j_{k^{0}k_{R}q}}{2}} \frac{\frac{j_{k^{0}k_{R}}}{2}}{2}$$

$$n (eV_{k_{R}}) (k_{R}) (k_{R}) + \frac{1}{2} (k_{R}) n_{L} (k_{R}) N_{L} (k_{R})$$

$$n_{R} (k_{R}) [I - n_{L} (k_{R})] N_{L} (k_{R}) + \frac{1}{2} (k_{R}) n_{L} (k_{R}) (k_$$

To make our analysis transparent, we rewrite the magnon-assisted current as the sum of two parts,

$$\begin{split} \mathtt{I}_{A\,\mathrm{P}} &= \mathtt{I}_{A\,\mathrm{P}}^{\,(i;i)} + \mathtt{I}_{A\,\mathrm{P}}^{\,(ii;iv)} + \mathtt{I}_{A\,\mathrm{P}}^{\,(v;v\,i)} + \mathtt{I}_{A\,\mathrm{P}}^{\,(v;iv\,ii)} \\ &= \mathtt{I}_{A\,\mathrm{P}}^{\,\mathrm{spont}} + \mathtt{I}_{A\,\mathrm{P}}^{\,\mathrm{stim}} \textbf{;} \end{split}$$

the rst of which, labelled  $I_{AP}^{spont}$ , does not contain any m agnon occupation numbers and represents spontaneous em ission processes,

$$I_{AP}^{\text{spont}} = \frac{e}{h} \frac{(T_{++} + T_{-})}{2 N} \int_{1}^{2} \int_{0}^{+1} \frac{d}{d!} \frac{d!}{d!} (!)$$

$$n_{L}() [L_{R}(eV_{-})]$$

$$[L_{R}(eV_{-})] (eV_{-}); (20)$$

where (!) =  $\Pr_{q}$  (!  $l_{q}$ ) is the magnon density of states that we assume to be the same on both sides of the junction. Since our main aim is to demonstrate the existence of an e ect, we choose the simple example of a bulk, three-dimensionalm agnon density of states. We assume a quadratic magnon dispersion,  $l_{q} = D q^{2}$ , and apply the D ebye approximation with a maximum magnon energy  $l_{D} = D (6^{2} = v)^{2=3}$  where v is the volume of a unit cell. This enables us to express the magnon density of states as (!) =  $(3=2)N ! {}^{1=2}=!_{D}^{3=2}$ . The term  $I_{AP}^{\text{spont}}$  is only non-zero for nite voltage. We calculate it in two di erent limits, small temperature di erence T T and large temperature di erence T = T; T = 0.

$$I_{AP}^{spont} = \frac{e^2}{h} \frac{V}{(T_{++} + T)} \frac{k_B T_L}{!_D}^{3=2}$$
$$\frac{3}{4} \left(\frac{3}{2}\right) \frac{3}{2} \frac{1}{2}; p \frac{T}{2}; T = T ; (21)$$

where (x) is the gam m a function and (x) is R iem ann's zeta function.<sup>35</sup>

The second term, labelled  $I_{A\,P}^{stim}$ , contains all the magnon occupation numbers and it represents absorption and stimulated emission processes,

$$I_{AP}^{stim} = \frac{e}{h 2} \frac{1}{N} \int_{1}^{Z_{+1}} \frac{d}{d} d! (!)$$

$$[h_{L}() n_{R}(eV + !)][T_{+}N_{L}(!) + T_{R}(!)]$$

$$+ [h_{L}() n_{R}(eV !)][T_{+}N_{R}(!) + T_{L}(!)] :$$
(22)

It vanishes in the lim it of zero tem perature on both sides of the junction, but is non-zero for zero bias voltage in the presence of a tem perature di erence.  $I_{A\,P}^{stim}$  may be written explicitly for arbitrary bias voltage and tem peratures,

$$I_{AP}^{stim} = \frac{e}{h} \frac{3}{4 \cdot !_{D}^{3=2}} 
 n 
 eV (T_{++} + T_{-}) (\frac{3}{2}) (\frac{3}{2}) (k_{B} T_{L})^{3=2} + (k_{B} T_{R})^{3=2} 
 (T_{++} - T_{-}) (\frac{5}{2}) (\frac{6}{2}) (k_{B} T_{L})^{5=2} (k_{B} T_{R})^{5=2} \overset{O}{:} (23)$$

#### D.Calculation of the therm opower

The therm opower  $S_{A\,P}$  is determ ined by setting the total current to zero,  $I_{A\,P}^{(1)}$  +  $I_{A\,P}^{\text{spont}}$  +  $I_{A\,P}^{\text{stim}}$  = 0, and nding the voltage V induced by the tem perature di erence T,  $S_{A\,P}$  = V=T. In general we nd

$$S_{AP} = \frac{k_B}{e} \frac{C (T_{++} T) m (T)}{[T_{+} + T_{+} + B (T_{++} + T) m (T)]}; (24)$$

This is the main result of the paper, describing junctions between ferrom agnets of arbitrary polarization strength ranging from weak ferrom agnets to half-metals. The factors C and B are dependent on the ratio T=T. We evaluate them in the limits of small, T T, and large, T = T  $_{\rm L}$  = T,  $T_{\rm R}$  = 0, temperature di erence:

$$C = \frac{\frac{6}{2}}{\frac{2}{2}}, \qquad \begin{array}{c} 15=8 \ ; & T & T \\ 3=4 \ ; & T = T \end{array}; \qquad (25)$$

$$B = \frac{3=2}{(3)}; p = \frac{T}{2}; T = T$$
(26)

The function m(T) in Eq. (24) is the change in the magnetization due to therm alm agnons at temperature T (B loch's T<sup>3=2</sup> law),<sup>36</sup>

$$m (T) = \frac{1}{N} \int_{0}^{Z_{1}} d! (!) N_{L} (!)$$
$$= \frac{3}{2} (\frac{3}{2}) (\frac{3}{2}) \frac{k_{B} T}{!_{D}} \stackrel{3=2}{:} (27)$$

The therm opower is nite because the current  $I_{A\,P}^{stim}$  contains a term (last line in Eq. (23)) that depends on the temperature di erence. It arises from the di erence in the therm aldistribution of magnons N<sub>L</sub> (!) N<sub>R</sub> (!) and the process of therm al equilibration between two baths of magnons held at di erent temperatures, which is mediated by electrons, results in a current. The origin of the factor T<sub>++</sub> T in the numerator of Eq. (24) can be understood in the follow ing way. In the Electron' processes in Figure 2, which contribute to T<sub>++</sub>, an increase

in the number of magnons in one electrode is achieved by accepting electrons from the other electrode. On the other hand, in the the hole' processes in Figure 3, which contribute to T  $\,$ , an increase in the number of magnons in one electrode is achieved by injecting electrons into the other electrode. Hence the contributions of  $T_{++}$  and T proportional to T in the current Eq. (23) appear with opposite signs.

The sign of the therm opower, Eq. (24), is specied for electron (charge e) transfer processes and under the assumption that the exchange between conduction band and core electrons has a ferrom agnetic sign. For antiferrom agnetic exchange, the overall sign of the therm opower would be opposite. For example, processes (i) and (ii) in Fig.2, would involve m agnons on the opposite side of the junction, hence the current  $I_{AP}^{(i;ii)}$  would be determ ined by m agnon occupation numbers N<sub>L</sub>(q). Note also that we considered a bulk, three-dimensional magnon density of states, but in general the magnon spectrum.

### 1. Uniform ly transparent interface

W e model di erent types of interface by introducing a dependence of the tunneling matrix elements  $t_{k_L;k_R}$  on the wavevectors  $k_L = (k_L^{jj};k_L^z)$  and  $k_R = (k_R^{jj};k_R^z)$ , where  $k_{L(R)}^{jj}$  is the component parallel to the interface and  $k_{L(R)}^z$  is the perpendicular component. For a uniform ly transparent interface of area A such that the parallel component of momentum is conserved, we set the dimensionless tunneling factor, Eq. (8), equal to

$$\mathbf{\hat{J}}_{k_{L}^{jj};k_{R}^{jj}}\hat{\mathbf{f}}^{2} = \mathbf{\hat{J}}^{2}_{k_{L}^{jj};k_{R}^{jj}};$$
(28)

so that

$$T \circ 4^{2} j_{2}^{2} \frac{A}{h^{2}} m inf ; \circ g$$
 (29)

where t represents the transparency of the interface and

is the area of the m axim al cross-section of the Ferm i surface of spins , \_+ > > 0. Then  $T_+ = T_+ =$  $T_- = 4^{-2} \pm^2_J (A_- =h^2)$  and  $T_{++} = 4^{-2} \pm^2_J (A_- =h^2)$ . In the regime 1 (1+ \_+= ) m (T), the therm opower Eq. (24) simplifies as

$$S_{AP} = C \frac{k_B}{e} \frac{(+)}{2} m (T):$$
 (30)

#### 2. Di usive tunnel barrier

W e use a m odel<sup>34</sup> for describing a strongly nonuniform interface which is transparent in a nite number of points only, random ly distributed over an area A. Each transparent point is treated as a defect which causes electron scattering in the plane parallel to the interface and the tunneling m atrix element is a m atrix element of the total scattering potential determ ined with the use of plane w aves,

$$t_{k_{L}^{jj},k_{R}^{jj}}^{ij} = \frac{a}{A} t_{j} \exp i h^{-1} (k_{L}^{jj} k_{R}^{jj}) \mathbf{x}_{j}^{ij}; \quad (31)$$

where  $r_j$  is the position of the jth contact with area a  $^2_F$ . A product of two tunneling matrix elements, averaged with respect to the position of each defect, will be large only if the total phase shift is zero which corresponds to scattering from the same defect,

$$h \mathcal{J}_{K_{L}^{jj},k_{R}^{jj}} f i = \frac{a}{A}^{2} \mathcal{J} f; \qquad (32)$$

where  $p_{ij} = A$  accounts for a reduced e ective area and  $f_{ij} = f_{ij} f_{ij} f_{ij}$  is an e ective transparency. This means that

$$I \circ 4^{2} \pm j^{2} \frac{a}{h^{2}} \frac{a \circ}{h^{2}} :$$
 (33)

W e assume that the densities of states in the spin band are equal on both sides of the junction so that  $T_+ = T_+$ . In the regime 1 (  $_+ = + = _+$ ) m (T), the therm opower Eq. (24) simplies as

$$S_{AP} = C \frac{k_B}{e} \frac{\frac{2}{+}}{2} \frac{2}{+} m (T):$$
 (34)

# III. THERM OPOW ER OF A PARALLEL JUNCTION

For parallel orientation of the magnetic polarizations of the ferrom agnets, we nd that the contribution of magnon-assisted tunneling to the therm opower is zero (upto the lowest order in the electron-magnon interaction). We consider the majority electrons on both sides of the junction to be spin up and them inority electrons to be spin down, and the technical details of the calculation of the current are similar to those described previously for the antiparallel orientation. There is a rst order, elastic contribution  $I_p^{(1)}$ ,

$$I_{p}^{(1)} = \frac{e^{2}}{h}V(T_{++} + T) + O = \frac{e}{h}\frac{k_{B}^{2}T}{F}$$
; (35)

involving tunneling between majority states on the left and right,  $T_{++}$ , and tunneling between minority states, T, without any spin ip processes. The rst term in Eq. (35) corresponds to a large current response to nite voltage whereas the second term arises from the energy dependence of the electronic density of states near the Ferm i energy.

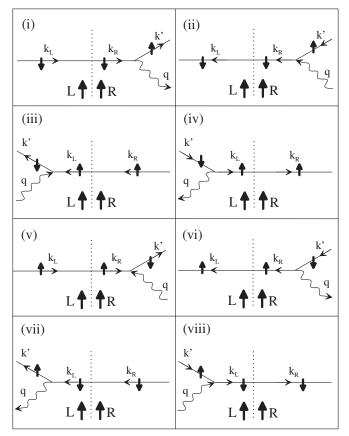


FIG.4. Schem atic ofm agnon-assisted tunneling across a junction with ferrom agnetic electrodes in the parallel con guration. Eight processes which, to low est order in the electron-m agnon interaction, contribute to m agnonassisted tunneling. (i) - (iv) involve transitions between m inority states on the left and m a prity states on the right via a virtual interm ediate state. (v) - (viii) involve transitions between m a prity states on the left and m inority states on the right via a virtual interm ediate state.

To the lowest order in the electron-magnon interaction there are eight magnon-assisted tunneling processes which are shown schematically in Figure 4. The top four processes, (i)-(iv), involve transitions between minority states on the left and majority states on the right, whereas the lower four processes, (v)-(viii), involve transitions between majority states on the left and minority states on the right. The overall contribution to the thermopower is zero because the stimulated emission part of the current does not depend on the temperature di erence across the junction,

$$I_{p}^{\text{stim}} = \frac{e}{h} \frac{3}{4 \ !_{p}^{3=2}}$$
n
eV (T<sub>+</sub> + T<sub>+</sub>) ( $\frac{3}{2}$ ) ( $\frac{3}{2}$ ) ( $k_{B}$  T<sub>L</sub>)<sup>3=2</sup> + ( $k_{B}$  T<sub>R</sub>)<sup>3=2</sup>
(T<sub>+</sub> T<sub>+</sub>) ( $\frac{5}{2}$ ) ( $\frac{6}{2}$ ) ( $k_{B}$  T<sub>L</sub>)<sup>5=2</sup> + ( $k_{B}$  T<sub>R</sub>)<sup>5=2</sup> (36)

This can be understood by examining the processes in Figure 4. The top four processes (i)-(iv), which have

m inority states on the left and majority on the right, all produce terms proportional to T $_+$ . Two of them, (i) and (ii), are 'electron' type processes in which an increase (decrease) in the number of magnons on the right is achieved by accepting (injecting) electrons from (into) the left, but the other two, (iii) and (iv), are hole' type processes in which an increase (decrease) in the number of magnons on the left is achieved by injecting (accepting) electrons into (from ) the right. Therefore the term proportional to T $_+$  in the last line of  $I_p^{\rm stim}$ , Eq. (36), does not depend on the tem perature di erence but a sum  $(k_B T_L)^{5=2} + (k_B T_R)^{5=2}$ . The same is true for the lower four processes in F igure 4, (v) – (viii), that produce term s proportional to  $T_+$ .

#### IV . C O N C LU S IO N

As shown above, the therm opower of a tunnel F-F junction in the parallel con guration,  $S_P = k_B^2 T = (e_F)$ , is smaller than the contribution of magnon-assisted transport to the therm opower  $S_{AP}$  in the antiparallel con guration, Eq. (1). As the relative polarizations of ferrom agnetic layers can be manipulated by an external magnetic eld, the large di erence  $S = S_{AP} = S_P$  results in a magnetotherm opower e ect. As a rough estimate, we take  $_F = 5eV$  and  $m = 7.5 = 10^6 T^{3=2}$  (for a ferrom agnet such as Ni, Ref. 36) to give  $S_{AP} = 3 V K^{-1}$  and  $S_P = 0.5 V K^{-1}$  at T = 300K.

As an extrem e example, we predict a giant magnetotherm opower for a junction between two half-metallic ferrom agnets. In a half-metal the splitting between the majority and minority conduction bands is greater than  $_{\rm F}$  measured from the bottom of the majority band so that only majority carriers are present at the Ferm i energy. In this case  $T_+ = T_+ = T_- = 0$  in Eq. (24) and, in the linear regime  $T_- T_{\rm L}$ ,

$$S_{AP} = 0.64 \frac{k_B}{e}; S_P \frac{k_B^2 T}{e_F}:$$
 (37)

This result is independent of tem perature and of the speci chalfm etallicm aterial, and it represents a giantm agnetotherm opower e ect S  $_{\rm A\,P}$   $_{\rm 55}$  V K  $^1$ .

A strong polarization dependence of the therm opower, S  $S_{AP}$ , enables one to separate the interface contribution to the therm opower from e ects arising from a nite tem perature gradient in the reservoirs. We assume in our analysis that phonon-m ediated heat conduction is much lower than the electronic one, and that a fast tem perature equilibration inside the ferrom agnetic m etal m akes a nite tem perature drop across the tunnel barrier possible. Furtherm ore, the predicted interface m agnetotherm opower will be m ost pronounced in a geom etry where the bottleneck for electron transport is also the bottleneck for therm altransport: in a sm allarea m esoscopic junction, ideally, in a suspended STM -type geom etry.

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